**ON Semiconductor** 

Is Now

# Onsemi

To learn more about onsemi<sup>™</sup>, please visit our website at <u>www.onsemi.com</u>

onsemi and ONSEMI. and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product factures, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and asfety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or by customer's technical experts. onsemi products and actal performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use onsemi products for any such unintended or unauthorized application, Buyer shall indemnify and hold onsemi and its officers, employees, subsidiari



Is Now Part of



# **ON Semiconductor**®

To learn more about ON Semiconductor, please visit our website at <u>www.onsemi.com</u>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor dates sheds, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor dates sheds and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use on similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor and its officers, employees, subsidiaries, affliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out or i, directly or indirectly, any lay bed ON Semiconductor and its officers, employees, ween if such claim alleges that ON Semiconductor was negligent regarding the d



# AN-9068 Gate Resistor Design Guidelines for SupreMOS<sup>®</sup> MOSFETs

#### Summary

The faster switching of power MOSFETs enables higher efficiency. power conversion However, parasitic components in the devices and boards are involving switching characteristics more as the switching speed increases. This creates unwanted side effects, like voltage spikes or poor EMI performance. To achieve balance, it is important to have optimized gate drive circuitry because a power MOSFET is a gate-controlled device. One of critical control parameters in gate-drive design is external series gate resistor (Rg). This note suggests minimum and maximum values of Rg for the SupreMOS® MOSFETs in hard-switching applications. As too small Rg results in excessive dv/dt across drain and source of the MOSFET during switching-off, low limit is a value that makes switching dv/dt within the specification in the datasheets. Silicon Carbide (SiC) Schottky barrier diode, Deuxpeed<sup>10</sup> rectifier, and STEALTH<sup>™</sup>2 diodes are used for clamp diode since the diode characteristics affect the dv/dt. Too large  $R_g$ causes loss and poor efficiency; therefore, the upper limit is chosen to have the same switching losses as the SuperFET<sup>®</sup> MOSFETs or competitors.

## Minimum Values According to dv/dt

Table 1 shows low limits of  $R_g$ . The unit of  $R_g$  in Table 1 is Ohm ( $\Omega$ ). Since the dv/dt varies by drain current level, it is tested with two conditions. For example, when using FCP76N60N with a SiC diode under half of rated current, at least 13 $\Omega$  or larger  $R_g$  is required to keep the switching dv/dt under 50V/ns during switching-off transient.

The dv/dt with a SiC diode is lower than dv/dt with other diodes due to the bigger junction capacitance of SiC SBD. A gap of the dv/dt values is getting larger at lower drain current level and smaller  $R_g$ . This is because, at lower current, the dv/dt is relatively low and the effect of output capacitance of the MOSFET and diode junction capacitance on the dv/dt becomes more significant.

If a specific  $R_g$  value is needed for other dv/dt not shown in Table 1, it can be selected by referring to Figure 13 through Figure 18.

$R_g$ at 1/2 of $I_d$	dv/dt<100V/ns			dv/dt<50V/ns		
	SiC	Dx	S2	SiC	Dx	S2
FCP9N60N	0	0	0	0	33	36
FCP11N60N	0	0	0	0	33	36
FCP13N60N	0	0	0	27	36	39
FCP16N60N	0	0	6.8	27	33	36
FCP22N60N	0	13	18	27	36	39
FCP25N60N	0	13	18	22	36	36
FCA36N60N	6.8	13	16	22	33	36
FCA47N60N	6.8	11	13	22	27	27
FCA76N60N	6.8	6.8	6.8	13	16	16
$R_g$ at Rated I <sub>d</sub>	dv/dt<100V/ns			dv/dt<50V/ns		
	SiC	Dx	S2	SiC	Dx	S2
FCP9N60N	6.8	13	18	27	43	47
FCP11N60N	6.8	13	18	27	36	39
FCP13N60N	10	16	22	30	43	47
FCP16N60N	10	13	18	27	36	39
FCP22N60N	10	16	22	30	43	47
FCP25N60N	13	16	18	27	39	43
FCA36N60N	13	16	18	22	36	39
FCA47N60N	11	13	13	16	27	27
FCA76N60N	6.8	6.8	10	13	18	18

#### Table 1. Minimum R<sub>q</sub> Guidelines Ohms

# Upper Limits Considering Switching Losses

When the SuperFET® MOSFET or other previousgeneration power MOSFET is directly replaced with the SupreMOS MOSFET, switching losses are reduced, but the dv/dt may be higher. To control the dv/dt of SupreMOS MOSFETs, increased  $R_g$  is required. In this case, there should be a limit line for increasing the  $R_g$  or switching losses with SupreMOS MOSFET could be larger. Figure 19 through Figure 54 show switching losses according to  $R_g$  for each device.  $R_g$  for similar or less switching loss can be raised. For example, if 10 $\Omega$  is used for a FCA35N60 SuperFET MOSFET, 33 $\Omega$  achieves similar  $E_{ON}$  and  $E_{OFF}$  in under conditions of half of rated drain current and STEALTH<sup>TM</sup>2 diode.

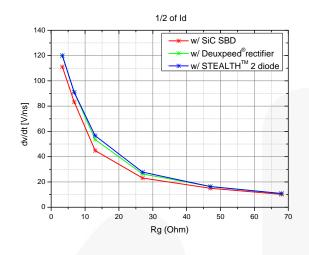
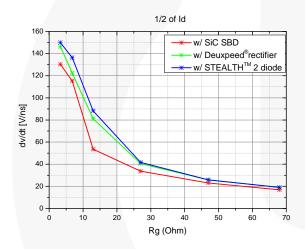


Figure 1. FCA76N60N dv/dt at Half ID





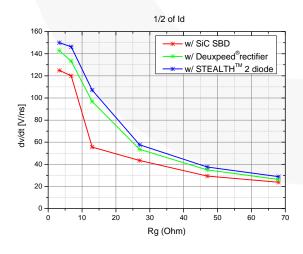


Figure 5. FCA36N60N dv/dt at Half I<sub>D</sub>

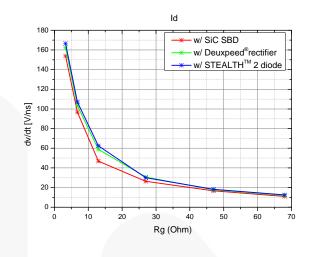
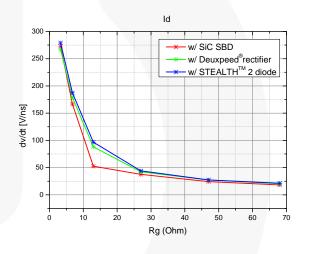


Figure 2. FCA76N60N dv/dt at Rated ID





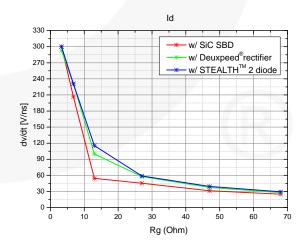


Figure 6. FCA36N60N dv/dt at Rated I<sub>D</sub>

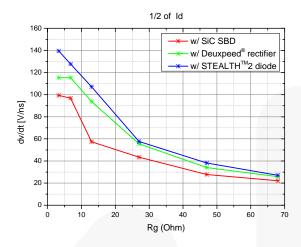


Figure 7. FCP25N60N dv/dt at Half I<sub>D</sub>

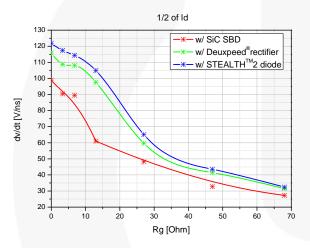


Figure 9. FCP22N60N dv/dt at Half I<sub>D</sub>

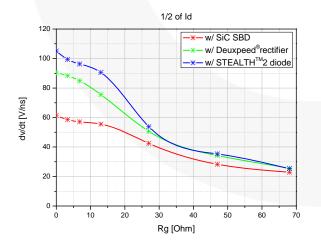


Figure 11.FCP16N60N dv/dt at Half  $I_D$ 

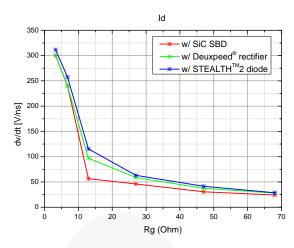


Figure 8. FCP25N60N dv/dt at Rated I<sub>D</sub>

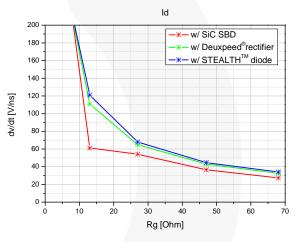


Figure 10.FCP22N60N dv/dt at Rated ID

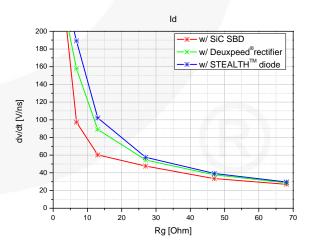


Figure 12.FCP16N60N dv/dt at Rated I<sub>D</sub>

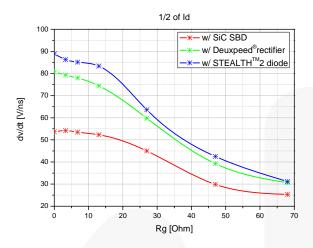


Figure 13.FCP13N60N dv/dt at Half ID

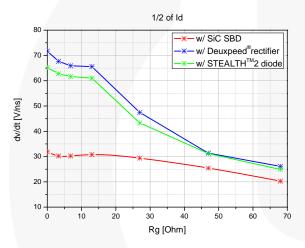


Figure 15.FCP11N60N dv/dt at Half I<sub>D</sub>

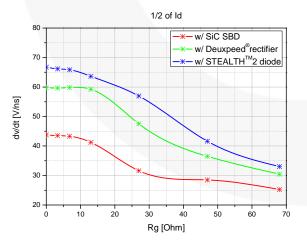


Figure 17.FCP9N60N dv/dt at Half I<sub>D</sub>

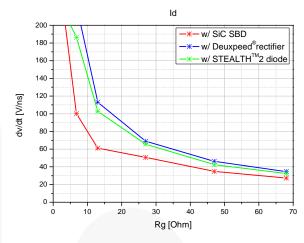


Figure 14.FCP13N60N dv/dt at Rated I<sub>D</sub>

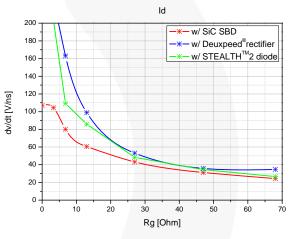


Figure 16.FCP11N60N dv/dt at Rated I<sub>D</sub>

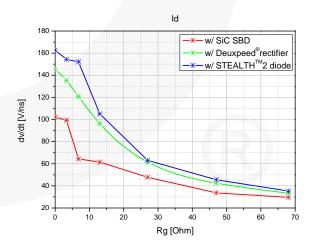


Figure 18.FCP9N60N dv/dt at Rated I<sub>D</sub>

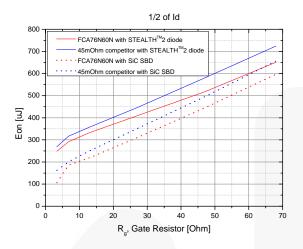


Figure 19.FCA76N60N EON vs. Competitor at Half ID

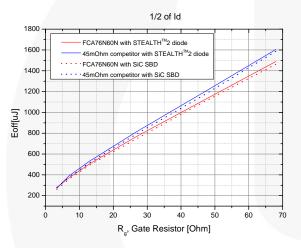


Figure 21.FCA76N60N EOFF vs. Competitor at Half ID

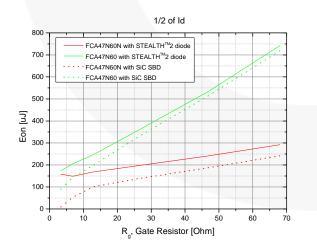


Figure 23.FCA47N60N E<sub>ON</sub> vs. FCA47N60 at Half I<sub>D</sub>

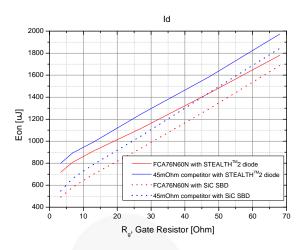
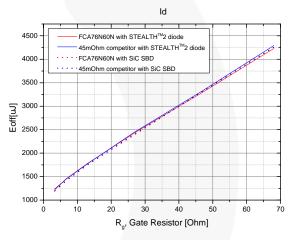


Figure 20.FCA76N60N E<sub>ON</sub> vs. Competitor at Rated I<sub>D</sub>



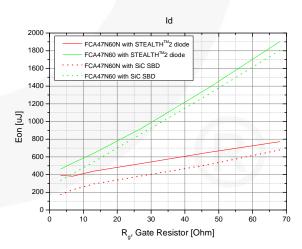
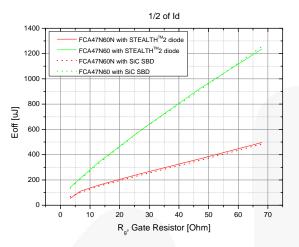


Figure 22.FCA76N60N EOFF vs. Competitor at Rated ID

Figure 24.FCA47N60N  $E_{\text{ON}}$  vs. FCA47N60 at Rated  $I_{\text{D}}$ 

© 2009 Fairchild Semiconductor Corporation Rev. 1.0.3 • 4/6/11





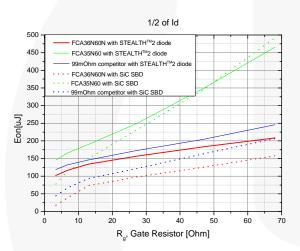


Figure 27.FCA36N60N E<sub>ON</sub> vs. FCA35N60 and Competitor at Half I<sub>D</sub>

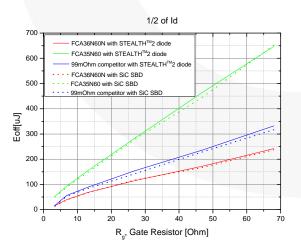


Figure 29.FCA36N60N E<sub>OFF</sub> vs. FCA35N60 and Competitor at Half I<sub>D</sub>

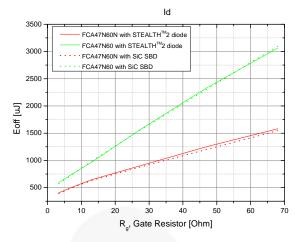


Figure 26.FCA47N60N EOFF vs. FCA47N60 at Rated ID

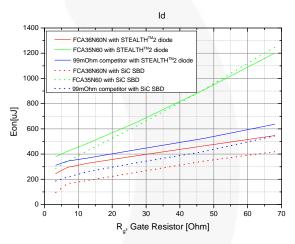
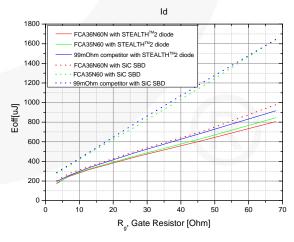
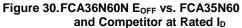
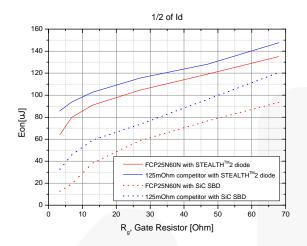


Figure 28.FCA36N60N E<sub>ON</sub> vs. FCA35N60 and Competitor at Rated I<sub>D</sub>









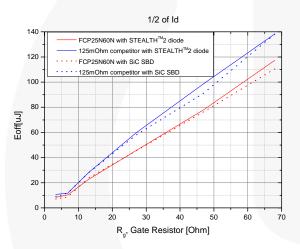


Figure 33.FCP25N60N EOFF vs. Competitor at Half ID

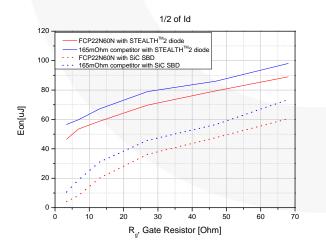


Figure 35.FCP22N60N  $E_{ON}$  vs. Competitor at Half  $I_D$ 

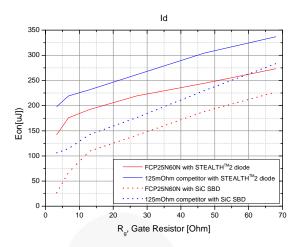
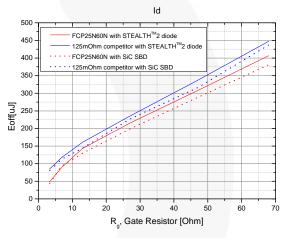


Figure 32. FCP25N60N EON vs. Competitor at Rated ID



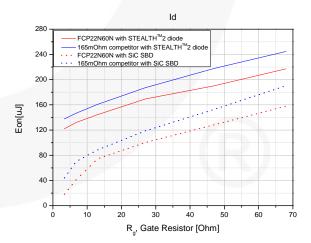
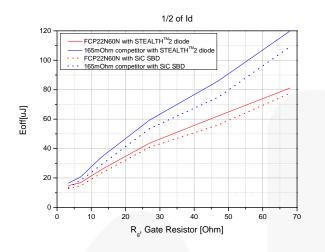
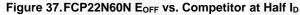
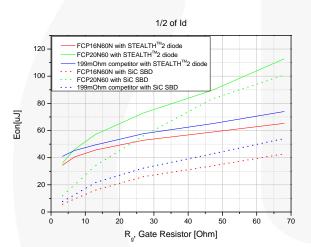


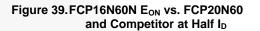


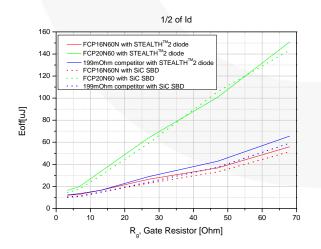
Figure 36.FCP22N60N  $E_{\text{ON}}$  vs. Competitor at Rated  $I_{\text{D}}$ 













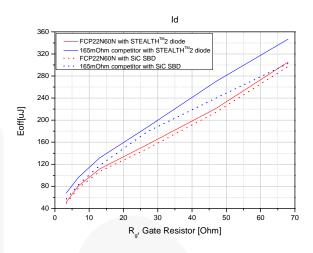


Figure 38.FCP22N60N EOFF vs. Competitor at Rated ID

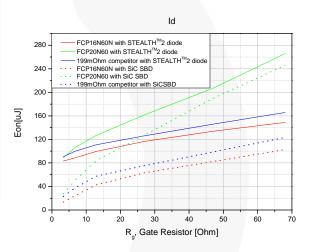


Figure 40.FCP16N60N E<sub>ON</sub> vs. FCP20N60 and Competitor at Rated I<sub>D</sub>

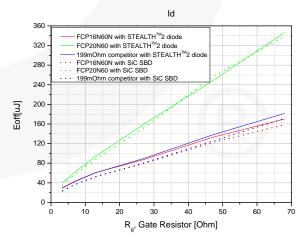


Figure 42. FCP16N60N E<sub>OFF</sub> vs. FCP20N60 and Competitor at Rated I<sub>D</sub>

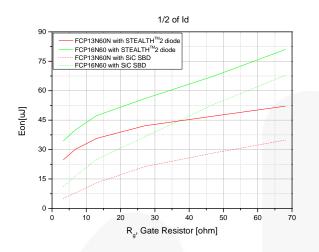


Figure 43.FCP13N60N  $E_{\text{ON}}$  vs. FCP16N60 at Half  $I_{\text{D}}$ 

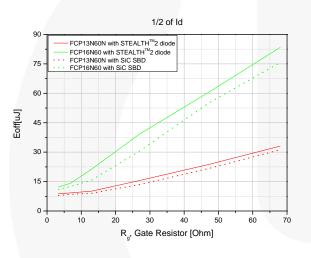


Figure 45.FCP13N60N EOFF vs. FCP16N60 at Half ID

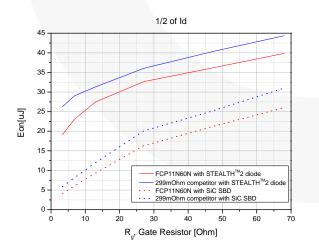


Figure 47.FCP11N60N  $E_{ON}$  vs. Competitor at Half  $I_D$ 

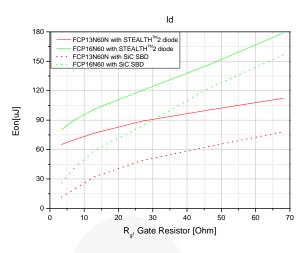
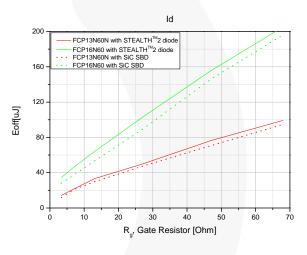


Figure 44. FCP13N60N EoN vs. FCP16N60 at Rated ID



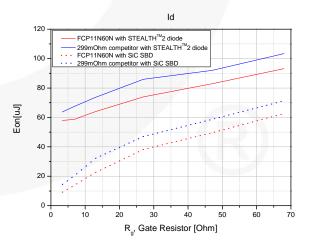
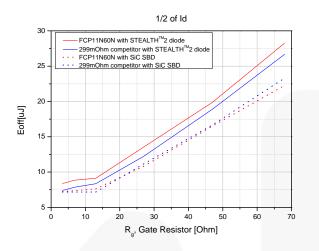
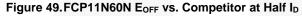
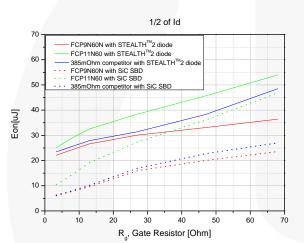


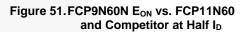
Figure 46.FCP13N60N EOFF vs. FCP16N60 at Rated ID

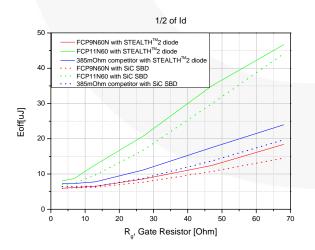
Figure 48.FCP11N60N  $E_{\text{ON}}$  vs. Competitor at Rated  $I_{\text{D}}$ 













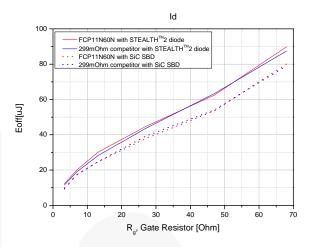


Figure 50.FCP11N60N EOFF vs. Competitor at Rated ID

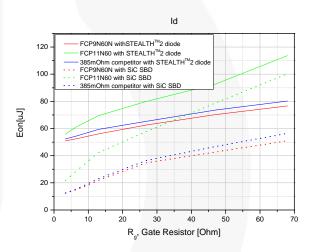


Figure 52.FCP9N60N E<sub>ON</sub> vs. FCP11N60 and Competitor at Rated I<sub>D</sub>

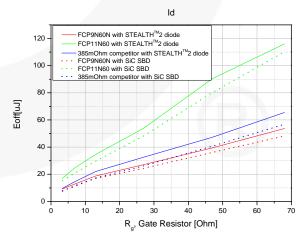


Figure 54.FCP9N60N E<sub>OFF</sub> vs. FCP11N60 and Competitor at Rated I<sub>D</sub>

#### **Related Datasheets**

FCA76N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCH76N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCH76N60NF- 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCH47N60N-600V N-Channel SupreMOS<sup>®</sup> MOSFET FCH47N60NF-600V N-Channel SupreMOS<sup>®</sup> MOSFET FCB36N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP36N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCA36N60NF – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCH25N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP25N60N F102 – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCI25N60N F102 – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP22N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCPF22N60NT – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCA22N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCH22N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP16N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCPF16N60NT – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCA16N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP13N60N- 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCPF13N60NT – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP11N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCPF11N60NT – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCP9N60N – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCPF9N60NT – 600V N-Channel SupreMOS<sup>®</sup> MOSFET FCD9N60NTM – 600V N-Channel SupreMOS<sup>®</sup> MOSFET

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

APPLICATION NOTE

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor has against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death ass

#### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81-3-5817-1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

© Semiconductor Components Industries, LLC